

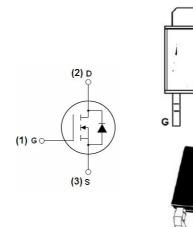
# Product data sheet

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# Schematic diagram



#### FEATURE

- Excellent package for good heat dissipation
- Ultra low gate charge
- Low reverse transfer capacitance
- Fast switching capability
- Avalanche energy specified

VBR:100V RDS:70MR@10V ID:15A



#### MAXIMUM RATINGS ( $T_a=25^{\circ}C$ unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V <sub>DS</sub>	100	V
Gate-Source Voltage	V <sub>GS</sub>	±20	V
Continuous Drain Current	I <sub>D</sub> (1)	15	A
Pulsed Drain Current	I <sub>DM</sub> ②	60	A
Single Pulsed Avalanche Energy	E <sub>AS</sub> <sup>(3)</sup>	49	mJ
Power Dissipation	P <sub>D</sub> <sup>①</sup>	45	W
Thermal Resistance from Junction to Ambient	R <sub>0JA</sub> 6	100	°C/W
Thermal Resistance from Junction to Case	R <sub>eJC</sub> (1)	2.78	°C/W
Operating Junction and Storage Temperature Range	T <sub>J</sub> ,T <sub>stg</sub>	-55~+150	°C



MS15N10 Semiconductor Compiance

#### T<sub>a</sub>=25 $^{\circ}$ C unless otherwise specified

Parameter	Symbol	Test Condition		Min	Тур	Мах	Unit
Off characteristics							•
Drain-source breakdown voltage	V(BR) DSS	Vgs = 0V, Id =250µA		100			V
	I <sub>DSS</sub>	V <sub>DS</sub> =80V, V <sub>GS</sub> =0V	T <sub>J</sub> =25°C			1.0	- μΑ
Zero gate voltage drain current			T <sub>J</sub> =125°C			100	
Gate-body leakage current	I <sub>GSS</sub>	Vps =0V, Vgs =±20V				±100	nA
On characteristics ④							
Gate-threshold voltage	VGS(th)	VDS =V <sub>GS</sub> , ID =250µA		1.0	2.5	3.0	V
Static drain-source on-sate resistance	RDS(on)	Vgs =10V, Id =8A			70	100	mΩ
Dynamic characteristics <sup>⊕</sup> <sup>⑤</sup>	1	1					
Input capacitance	C <sub>iss</sub>	VDS =25V,VGS =0V, f = 100KHz			773	1500	pF
Output capacitance	Coss				46	92	
Reverse transfer capacitance	C <sub>rss</sub>				43	90	
Gate resistance	Rg	f =1MHz			1.5		Ω
Switching characteristics <sup>④ ⑤</sup>	1	1				<u> </u>	
Total gate charge	Qg	V <sub>GS</sub> =10V, V <sub>DS</sub> =50V, I <sub>D</sub> =10A			18	36	nC
Gate-source charge	Q <sub>gs</sub>				2.8	5.6	
Gate-drain charge	Q <sub>gd</sub>				7.4	14.8	
Turn-on delay time	t <sub>d(on)</sub>	V <sub>DD</sub> =25V,R <sub>L</sub> =5Ω, V <sub>GS</sub> =10V,R <sub>G</sub> =1.0Ω			15		
Turn-on rise time	tr				33		- ns
Turn-off delay time	td(off)				41		
Turn-off fall time	tr				6		
Drain-Source Diode Characteristics	•						
Drain-source diode forward voltage	V <sub>SD</sub> <sup>(4)</sup>	VGS =0V, I <sub>S</sub> =8A				1.2	V
Continuous drain-source diode forward current	Is <sup>1</sup>					15	A
Pulsed drain-source diode forward current	I <sub>SM</sub> <sup>②</sup>					60	A

Notes:

1. T<sub>C</sub>=25°C Limited only by maximum temperature allowed.

2.  $P_W \le 10 \mu s$ , Duty cycle  $\le 1\%$ .

3. EAS condition:  $V_{DD}$ =25V,  $V_{GS}$ =10V, L=0.5mH, Rg=25 $\Omega$  Starting T<sub>J</sub> = 25°C.

4. Pulse Test : Pulse Width≤300µs, duty cycle ≤2%.

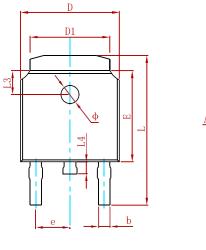
5. Guaranteed by design, not subject to production.

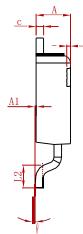
6. The value of RθJA is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with Ta=25°C.



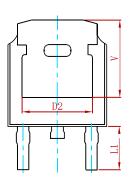


# PACKAGE MECHANICAL DATA



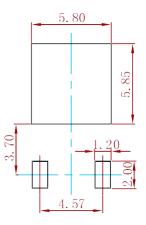


h



Symphol	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min.	Max.	Min.	Max.	
A	2.200	2.400	0.087	0.094	
A1	0.000	0.127	0.000	0.005	
b	0.635	0.770	0.025	0.030	
С	0.460	0.580	0.018	0.023	
D	6.500	6.700	0.256	0.264	
D1	5.100	5.460	0.201	0.215	
D2	4.830 REF.		0.190 REF.		
E	6.000	6.200	0.236	0.244	
е	2.186	2.386	0.086	0.094	
L	9.712	10.312	0.382	0.406	
L1	2.900 REF.		0.114 REF.		
L2	1.400	1.700	0.055	0.067	
L3	1.600 REF.		0.063 REF.		
L4	0.600	1.000	0.024	0.039	
Φ	1.100	1.300	0.043	0.051	
θ	0°	8°	0°	8°	
h	0.000	0.300	0.000	0.012	
V	5.250 REF.		0.207	REF.	

### Suggested Pad Layout



Note:

1.Controlling dimension:in millimeters.

2.General tolerance:± 0.05mm

3. The pad layout is for reference purposes only.

#### **REEL SPECIFICATION**

P/N	PKG	QTY
MS15N10	TO-252	2500



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